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BIB DATA SHEET

CONFIRMATION NO. 9797

FILING or 371(c)	CLASS	GROUP ART	UNIT	ATTORNEY DOCKET	
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APPLICANTS Kazuyoshi Okawa, Nerima-ku, JAPAN; Junko Ogino, Nerima-ku, JAPAN; Masayuki Yoshinaga, Nerima-ku, JAPAN; Hajime Honda, Nerima-ku, JAPAN; **CONTINUING DATA**** This application is a 371 of PCT/JP04/01805 02/18/2004 **FOREIGN APPLICATIONS**** "I FREQUIRED, FOREIGN FILING LICENSE GRANTED ** 04/10/2007					
N/	STATE OR COUNTRY JAPAN	SHEETS DRAWINGS 10	TOTA CLAIR 10	MS CLAIMS	
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Intellectual Property Law Office of David Lathrop No. 827 39120 Argonaut Way Fremont, CA 94538 UNITED STATES					
TITLE					
Semiconductor device test apparatus and method					
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